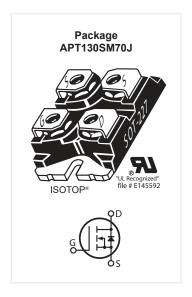


700V, 78A, 35mΩ

Silicon Carbide N-Channel Power MOSFET

DESCRIPTION

Silicon carbide (SiC) power MOSFET product line from Microsemi increase your performance over silicon MOSFET and silicon IGBT solutions while lowering your total cost of ownership for high-voltage applications.



FEATURES / TYPICAL APPLICATIONS

SiC MOSFET Features:

- Low on-resistance virtually independent on the ambient temperature
- · Low capacitances and low gate charge
- Fast switching speed due to low internal gate resistance (ESR)
- Stable operation at high junction temperature, Tj(max) = +175C
- · Fast and reliable body diode
- · Superior avalanche ruggedness

SiC MOSFET Benefits:

- High efficiency to enable lighter/compact system
- · Simple to drive and easy to parallel
- Improved thermal capabilities and lower switching losses
- Eliminates the need of external Free Wheeling Diode
- · Lower system cost of ownership

Applications:

- PV inverter, converter and industrial motor drives
- · Smart grid transmission & distribution
- · Induction heating, and welding
- · H/EV powertrain and EV charger
- · Power supply and distribution

MAXIMUM RATINGS

Symbol	Parameter	Ratings	Unit
V _{DSS}	Drain Source Voltage	700	V
	Continuous Drain Current @ T _c = 25°C	78	
l _D	Continuous Drain Current @ T _c = 100°C	55	А
I _{DM}	Pulsed Drain Current ^①	270	
V_{GS}	Gate-Source Voltage	-10 to +25	V
Б	Total Power Dissipation @ T _c = 25°C	273	W
P _D	Linear Derating Factor	1.82	W/°C

THERMAL AND MECHANICAL CHARACTERISTICS

Symbol	Characteristic	Min	Тур	Max	Unit	
$R_{ heta_{ exttt{JC}}}$	Junction to Case Thermal Resistance		0.34	0.55	°C/W	
T _j	Operating Junction Temperature	-55		175	00	
T _{stg}	Storage Junction Temperature Range	-55		150	°C	
W _T	Package Weight			1.03	oz	
Torque	Mounting Torque (SOT-227 Package), 6-32 or M3 screw		5	10	in·lbf	
			.56	1.13	N·m	

STATIC CHARACTERISTICS

Symbol	Parameter	Test Co	Min	Тур	Max	Unit	
V _{(BR)DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0V$	700			V	
R _{DS(on)}	Drain-Source On Resistance②	V _{GS} = 20\		35	45	mΩ	
$V_{GS(th)}$	Gate-Source Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 1 \text{mA}$		1.7	2.4		V
$\Delta V_{GS(th)}/\Delta T_{J}$	Threshold Voltage Temperature Coefficient				-5.1		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 700V V _{GS} = 0V	T _J = 25°C			100	
			T _J = 150°C			250	μΑ
I _{GSS}	Gate-Source Leakage Current	V _{GS} = +20V / -10V				±100	nA
ESR	Equivalent Series Resistance	f = 1MHz, 25mV, Drain Short			0.46		Ω

 $T_J = 25$ °C unless otherwise specified

DYNAMIC CHARACTERISTICS

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
C _{iss}	Input Capacitance	V - 0V V - 700V		3950		
C _{rss}	Reverse Transfer Capacitance	$V_{GS} = 0V, V_{DD} = 700V$ f = 1MHz		50		рF
C _{oss}	Output Capacitance	I = IWHZ		465		
Q_g	Total Gate Charge	V _{GS} = 0/20V		270		
Q _{gs}	Gate-Source Charge	V _{DD} = 466V		42		nC
Q_{gd}	Gate-Drain Charge	I _D = 60A		61		
t _{d(on)}	Turn-On Delay Time	V _{DD} = 466V		17		ns
t _r	Current Rise Time	V _{GS} = 0/20V		15		
t _{d(off)}	Turn-Off Delay Time	I _D = 60A		36		
t,	Current Fall Time	$R_{\rm G} = 1.5 \Omega^{\scriptsize \textcircled{3}}$		19		
E _{on2}	Turn-On Switching Energy ⁴	L = 115 μH Τ __ = 25°C		1060		1
E _{off}	Turn-Off Switching Energy	Freewheeling Diode = APT20SCE65B		305		μJ
t _{d(on)}	Turn-On Delay Time	V _{DD} = 466V		16		- ns
t _r	Current Rise Time	V _{GS} = 0/20V		15		
t _{d(off)}	Turn-Off Delay Time	$I_{D} = 60A$		39		
t,	Current Fall Time	$R_{\rm G} = 1.5 \Omega^{\scriptsize \textcircled{3}}$		21		
E _{on2}	Turn-On Switching Energy ⁴	L = 115 μH Τ _c = 150°C		965		
E _{off}	Turn-Off Switching Energy	Freewheeling Diode = APT20SCE65B		345		μJ

Source-Drain Diode Characteristics

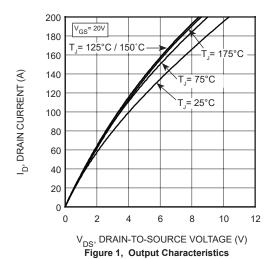
Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
V _{SD}	Diode Forward Voltage	I_{SD} = 60A, V_{GS} = 0V		3.85		V
t _{rr}	Reverse Recovery Time	I _{SD} = 60A, V _{DD} = 466V dI/dt = -1000A/μs		68		ns
Q _{rr}	Reverse Recovery Charge			460		nC
I _{rrm}	Reverse Recovery Current			15		Α

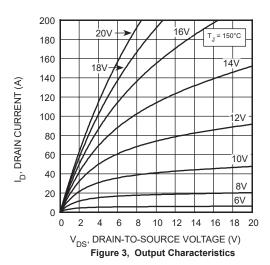
$T_J = 25^{\circ}C$ unless otherwise specified

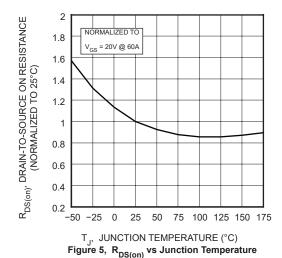
- 1 Repetitive Rating: Pulse width and case temperature limited by maximum junction temperature
- ② Pulse test: Pulse Width < 380µs, duty cycle < 2%.
- $\ensuremath{\ensuremath{\mathfrak{G}}}$ R $_{\ensuremath{\ensuremath{\mathsf{G}}}}$ is total gate resistance including internal gate driver impedance.
- (4) E_{on2} includes energy of APT20SCE65B free wheeling diode.

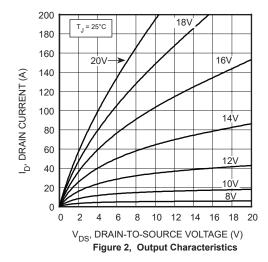
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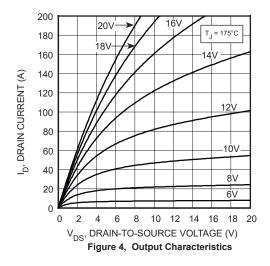


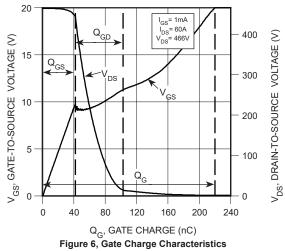












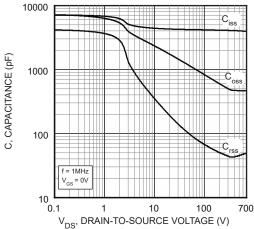
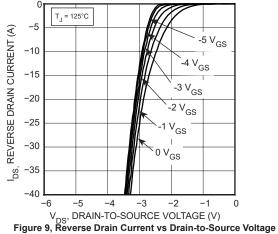
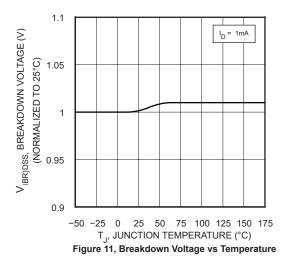
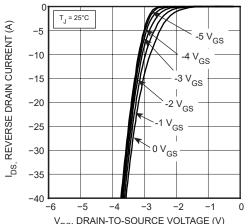


Figure 7, Capacitance vs Drain-to-Source Voltage

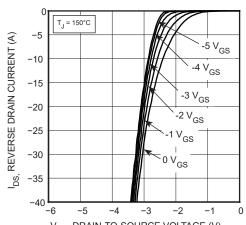


Third Quadrant Conduction





V_{DS}, DRAIN-TO-SOURCE VOLTAGE (V)
Figure 8, Reverse Drain Current vs Drain-to-Source Voltage **Third Quadrant Conduction**



 ${\rm V_{DS'}, DRAIN\text{-}TO\text{-}SOURCE\ VOLTAGE\ (V)}$ Figure 10, Reverse Drain Current vs Drain-to-Source Voltage **Third Quadrant Conduction**

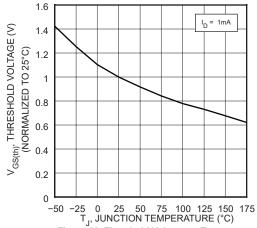
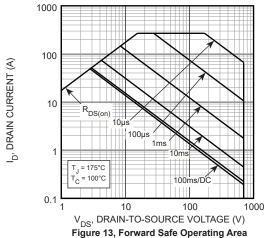
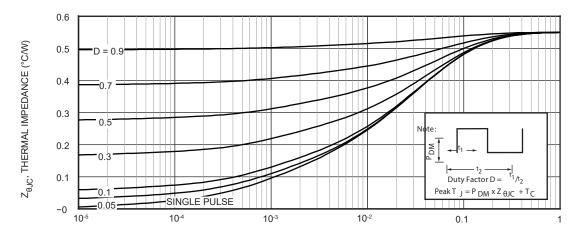


Figure 12, Threshold Voltage vs Temperature

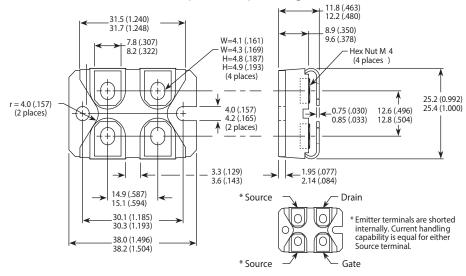






RECTANGULAR PULSE DURATION (SECONDS)
Figure 14, Maximum Effective Transient Thermal Impedance, Junction-To-Case vs Pulse Duration

SOT-227 (ISOTOP®) Package Outline



Dimensions in Millimeters (Inches)

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Power Matters."

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